

Correction to Single Defect Center Scanning Near-Field Optical Microscopy on Graphene

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Reference 29 was updated to the following: Gaudreau, L.; Tielrooij, K. J.; Prawiroatmodjo, G. E. D. K.; Osmond, J.; de Abajo, F. J. G.; Koppens, F. H. L. *Nano Lett.* **2013**, *13*, 2030–2035.

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